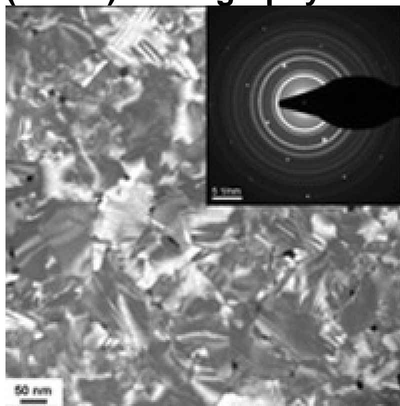
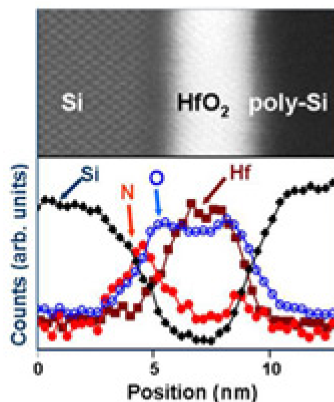
Scanning Transmission Electron Microscopy (STEM)

Selected Area Electron Diffraction (SAED) / Convergent Beam Electron Diffraction

(CBED) / Holography





Instruments

- FEI Tecnai F-30

Applications

- SAED and CBED Diffraction
- Crystal identification, orientation and strain
- Holography
- Resolution of phase-contrast
- Dopant profiling
- Scanning TEM
- Chemical Profiling

Technical Specifications

- 0.17 nm resolution (Scanning TEM)

For information or to arrange a demonstration please contact the New Pioneers in TEM Technology:

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